



PATENT
16CT03006

Ifw

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Shunichiro Tanigawa, et al.

Serial No. 10/816,626

Filed: April 2, 2004

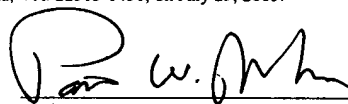
For: CORRECTION COEFFICIENT
CALCULATING METHOD FOR X-
RAY CT SYTEMS, BEAM
HARDENING POST-PROCESSING
METHOD THEREFOR, AND X-RAY
CT SYSTEM

Group Art Unit: 2882

Examiner: Artman, Thomas R.

CERTIFICATE OF MAILING

I certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA. 22313-1450, on July 29, 2005.


Patrick W. Rasche, Reg. No. 37,916

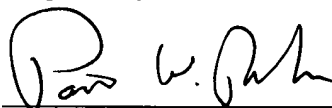
STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SIR:

The above-identified patent application was filed on April 2, 2004. Applicants respectfully request a status inquiry on the above-identified patent application. A copy of this request is enclosed for the purpose of reporting the results of the status inquiry.

Respectfully submitted,



Patrick W. Rasche, Reg. No. 37,916
ARMSTRONG TEASDALE LLP
One Metropolitan Square, Suite 2600
St. Louis, Missouri 63102-2740
(314) 621-5070